

wavelength, and  $\gamma = E_0/m$  the Lorentz contraction factor in the rest system of the electron.

Fig. 1 shows the optimal angle  $\theta^{opt}$  of the crystallographic axis of the SOS aligned crystal with the beam as a function of electron energy for which a CE is predicted at  $E_\gamma = 0.7E_0$  by equation (2). By changing the angle  $\theta$  of the crystallographic axis of the electron beam, the position of the hard photon peak can be varied. With the appropriate choice of  $\theta$  the intensity of the SOS radiation may exceed the Batho Haitlor radiation by an order of magnitude.

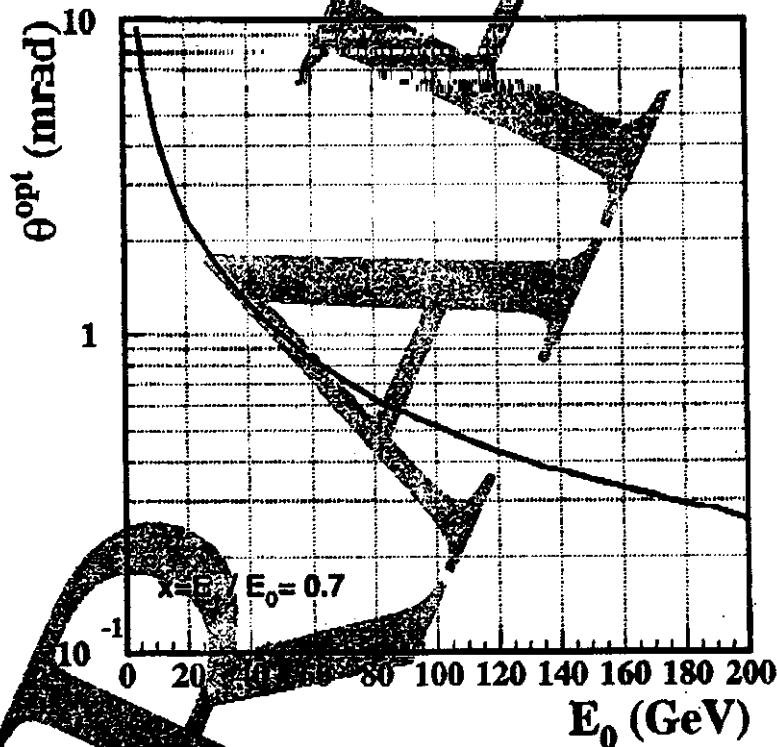


FIG. 1: Optimal angle  $\theta^{opt}$  between the electron direction in the (110) plane and the (100) axis of the silicon crystal as a function of electron energy  $E_0$ . The desired radiated photon energy is  $E_\gamma = 0.7E_0$ .

The radiation spectrum with the crystal aligned in SOS orientation has in addition to the CE a strong component at low frequency which is characteristic for channelling radiation. When the electron direction lines up with a crystallographic plane in the SOS orientation, the planar channelling condition is fulfilled. For channelling radiation the coherent length is much longer than the interatomic distances and the long range motion, characteristic for planar channelling electrons, becomes dominant over short range variations with the emission of low energy photons. Theoretical calculations predict a more intense soft photon

contribution with a high degree of linear polarization of up to 70%.

In this experiment we used a 1.5 cm thick Si crystal in 100 orientation. The 178 GeV electron beam had an angle of  $\theta = 0.3$  mrad to the crystal surface (100) axis and was directed along the (110) plane. The high energy peak in the CB spectrum is expected at a photon energy of  $E_\gamma = 125$  GeV (see Fig. 1). Under this condition the radiation is expected to be enhanced by about a factor 20 with respect to the Bethe-Heitler prediction for a randomly oriented crystalline Si target.

### III. EXPERIMENTAL SETUP

The NA59 experiment was performed in the North Arm of the CERN SPS, where unpolarized electron beams with energies above 100 GeV are available. We used a beam of 178 GeV electrons with angular divergence of  $\sigma_x = 48 \mu\text{rad}$  and  $\sigma_y = 35 \mu\text{rad}$  in the horizontal and vertical plane, respectively.

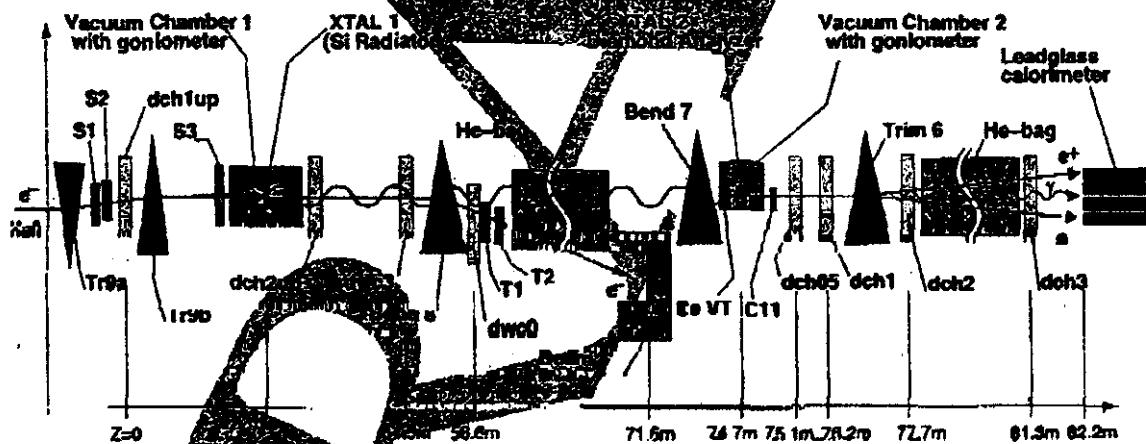


FIG. 2. NA59 experimental setup.

The experimental setup shown in Fig. 2 was also used to investigate the linear polarization of coherent bremsstrahlung (CB) and birefringence in aligned single crystals [7, 8]. This setup is ideally suited for detailed studies of the photon radiation and pair production processes in aligned crystals.

The main components of the experimental setup are: two goniometers with crystals mounted inside vacuum chambers, a pair spectrometer, a segmented leadglass calorimeter, wire chambers and plastic scintillators. In more detail a 1.5 cm thick Si crystal can be rotated in the first goniometer with  $2 \mu\text{rad}$  precision and serves as radiator. A multi-tile synthetic diamond crystal on the <sup>second</sup> first goniometer can be rotated with  $20 \mu\text{rad}$  precision and is used as the analyzer of the linear polarization of the photon beam.

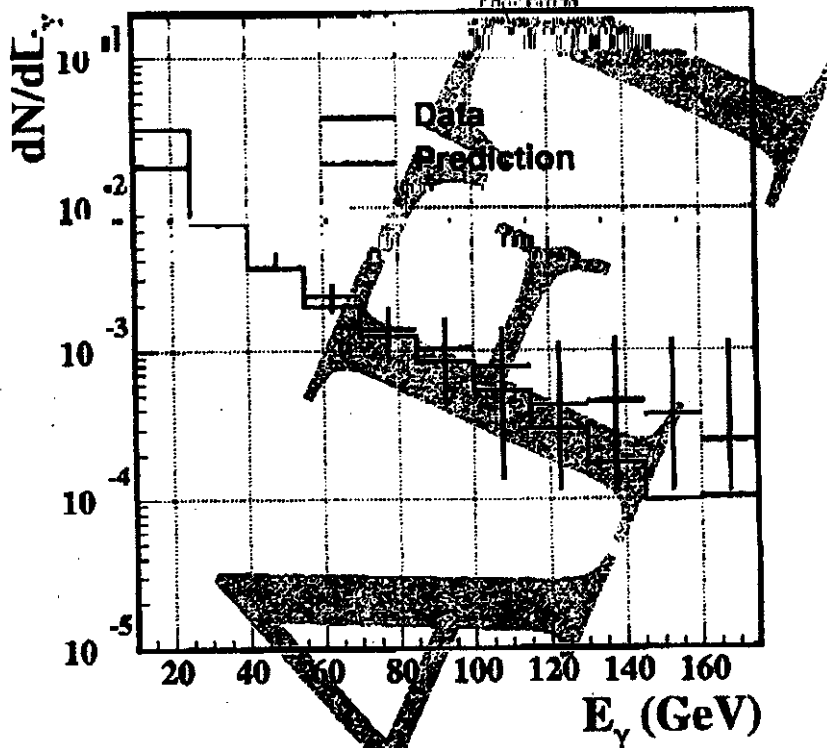


FIG. 3: Probability ( $dN/dE_\gamma$ ) of photon emission as a function of the photon energy  $E_\gamma$  in the SOS-aligned Si crystal for an electron of 178 GeV. The black crosses are the measurements and the red histogram represent the MC prediction.

For the chosen SOS orientation and the 1.5 cm thick Si crystal, the most probable radiative energy loss of the 178 GeV electrons is expected to be about 80%. The number of photons emitted by an electron that passes the crystal is high with an average multiplicity  $\geq 15$ , due to a large amount of low energy photons. Under these conditions a high energy photon (i.e. of 125 GeV) can only be emitted along the first part of the trajectory of an electron through the crystal, while soft photons will be emitted along the full length of it. Clearly, many electrons pass through the crystal and emit only soft photons.

We see that the expected SOS photon spectrum shows a smoothly decreasing distribution as shown in Fig. 3. The low energy region of the photon spectrum is saturated, due to the abundant production of low energy photons. Above 25 GeV there is satisfactory agreement between the expected photon spectrum (MC simulation) and the data measured with the pair spectrometer.

Fig. 4 shows the total radiated energy by the electrons that passed through the Si crystal. The peak of radiated energy is situated at 150 GeV, which means that each electron lost

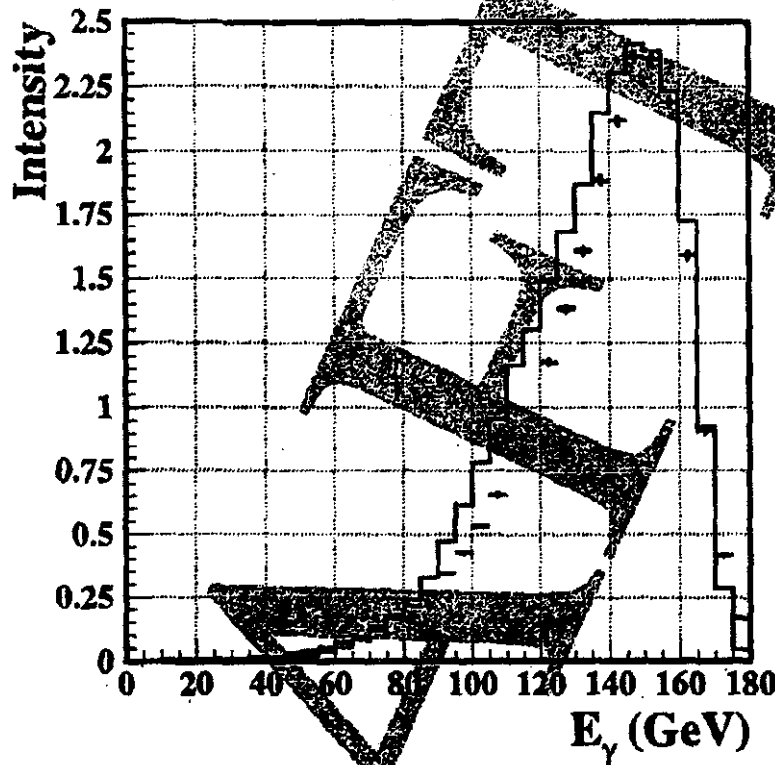


FIG. 4: Intensity of radiation ( $dN/dE_\gamma \times E_\gamma^{tot}$ ) as a function of the total radiated energy  $E_\gamma^{tot}$  in the SOS-aligned Si crystal for 100 GeV electrons. The black crosses are the measurements and the red histogram represent the MC prediction.

about 80% of its initial energy due to the large thickness of the radiator. This means that the effective radiation length of the oriented single crystal is several times shorter in comparison with the amorphous target. In the case of the electrons lost practically all their energy in the initial part of the trajectory after passing through the crystal.

The enhancement of the emission probability compared to the Bethe-Heitler prediction is given in Fig. 5 as a function of the total radiated energy. In the energy range of 140 to 160 GeV the enhancement factor is 18. The low energy region is depleted due to the large number of photons.

The expected linear polarization is shown in Fig. 6 as a function of photon energy. It is well known that channeling radiation in single crystals is linearly polarized and the low energy photons of 10-20 GeV are also predicted to be linearly polarized in the MC simulations. High energy photons are predicted with an insignificant polarization.

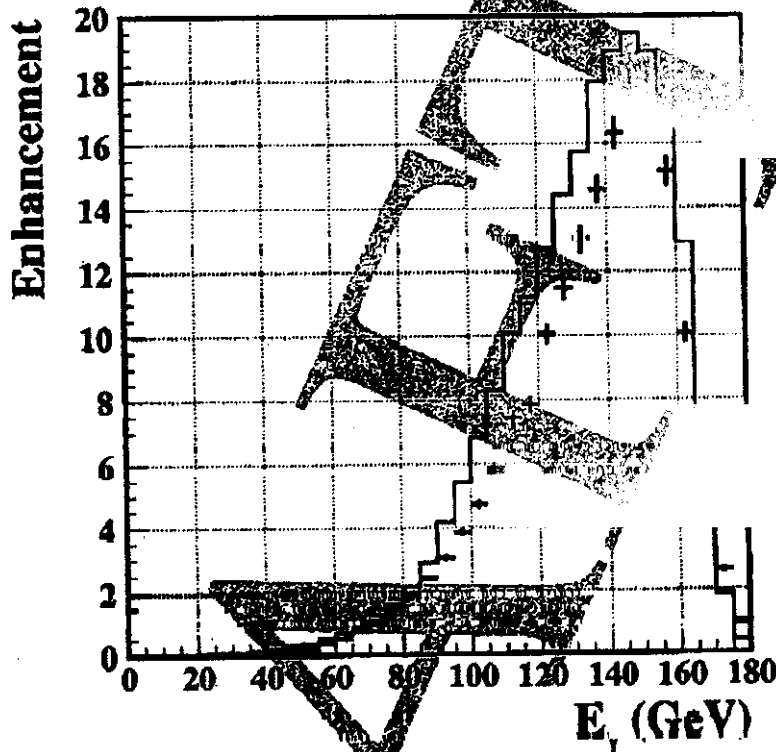


FIG. 5: Enhancement of the intensity with respect to the Bethe-Heitler prediction for randomly oriented polycrystalline Si as a function of the total radiated energy  $E_\gamma^{tot}$  in the SOS-aligned Si crystal by 178 GeV electrons. The black crosses are the measurements and the red histogram represent the MC prediction.

### B. Asymmetry Measurement

In this work, the photon polarization is always expressed using the Stoke's parametrization with the standard convention, where the total elliptical polarization is decomposed into two independent linear components and a circular component. In mathematical terms, one writes

$$P_{\text{linear}} = \sqrt{\eta_1^2 + \eta_3^2} \quad P_{\text{circular}} = \sqrt{\eta_2^2} \quad P_{\text{total}} = \sqrt{P_{\text{linear}}^2 + P_{\text{circular}}^2} \quad (2)$$

The angular settings were chosen to have the total linear polarization from the SOS radiation purely along  $\eta_3$ , that is  $\eta_1 = 0$ . The  $\eta_2$  component is also zero because the electron beam is unpolarized. The expected  $\eta_3$  component of the polarization shown is in Fig. 6.

In order to determine the linear polarization of the photon beam the method proposed in reference [15] with an oriented crystal was chosen. This method of measurement of the linear polarization of high energy photons is based on coherent  $e^+e^-$  pair production (CCP)

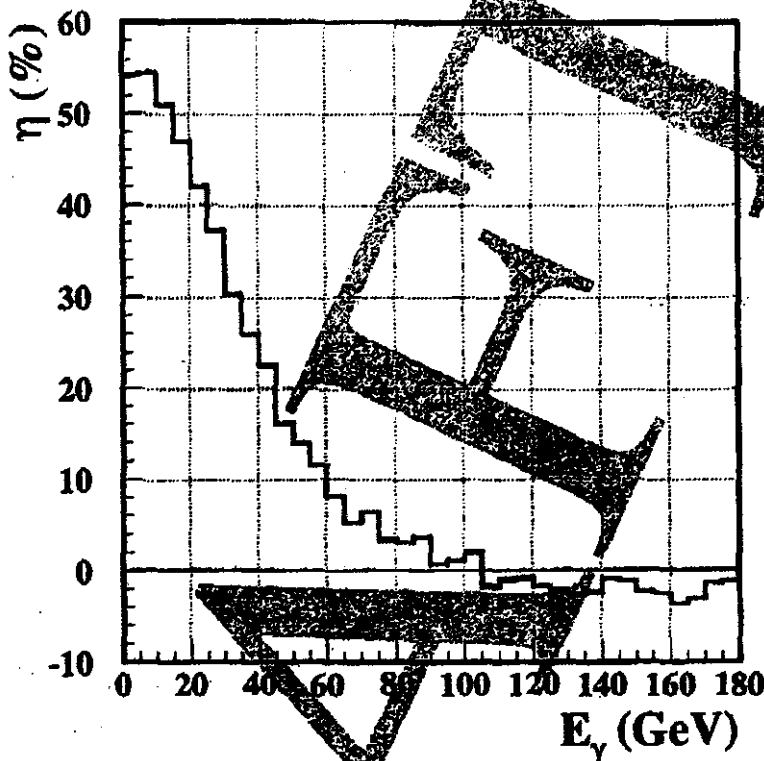


FIG. 6: Expected linear polarization as a function of the energy  $E_\gamma$  of the photons produced in the EOC-aligned Si crystal with 100 GeV electrons.

in single crystals which depends on the orientation of the reciprocal lattice vector and the linear polarization vector. This dependence of the CCP cross section on the linear polarization of the photon beam makes an oriented single crystal suitable as an efficient polarimeter for high energy photons.

The basic characteristic of the polarimeter is the analyzing power  $R$  of the analyzer crystal [15]. By choosing an appropriate crystal type and its orientation a maximal analyzing power can be obtained. The relevant experimental quantity is the asymmetry  $A$  of the cross sections  $\sigma(\gamma \rightarrow e^+e^-)$  for parallel and perpendicular polarization, where the polarization direction is defined with respect to a particular crystallographic plane of the analyzer crystal. The asymmetry is related to the linear polarization of the photon beam,  $P_\parallel$ , through:

$$A \equiv \frac{\sigma(\gamma_\perp \rightarrow e^+e^-) - \sigma(\gamma_\parallel \rightarrow e^+e^-)}{\sigma(\gamma_\perp \rightarrow e^+e^-) + \sigma(\gamma_\parallel \rightarrow e^+e^-)} = R \times P_\parallel. \quad (3)$$

The analyzing power  $R$  corresponds to the asymmetry expected for photons that are 100% linearly polarized perpendicular to the chosen crystallographic plane.

The existence of a strong anisotropy for the channeling of the  $e^+e^-$  pairs during their

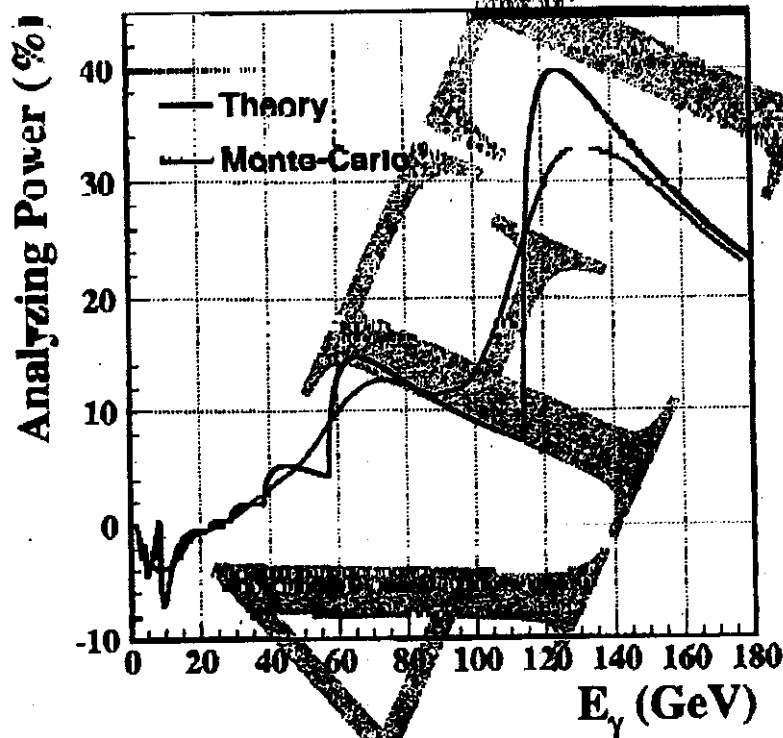


FIG. 7: Analyzing power  $R$  with the aligned diamond crystal as a function of the photon energy  $E_\gamma$  (black curve) for a monoenergetic photon beam without angular divergence and (red curve) for the Monte Carlo simulation of photons with the beam conditions in the NA49 experiment.

### CONCLUSION

Our experimental results show that the high energy photons emitted by electrons passing through our Si crystal radiator oriented in the SOS mode have a linear polarization smaller than 5% at a scattering angle level of 0.9. Earlier results by NA43 indicated that a large polarization could be obtained for high energy photons emitted by SOS oriented single crystals. These promising results for the production of highly polarized high energy photons are not confirmed in our experiment.

Note that recent calculations also predict that the linear polarization of high energy photons emitted in SOS orientation of the crystal is small compared to the polarization obtained with SOS orientation of the crystal. Photon emission by electrons traversing single crystals oriented in the SOS orientation has interesting peculiarities since three different radiation processes are involved: (1) Incoherent bremsstrahlung due to the electron scattering on potential fluctuations due to individual atoms. (2) Channelling radiation induced by the

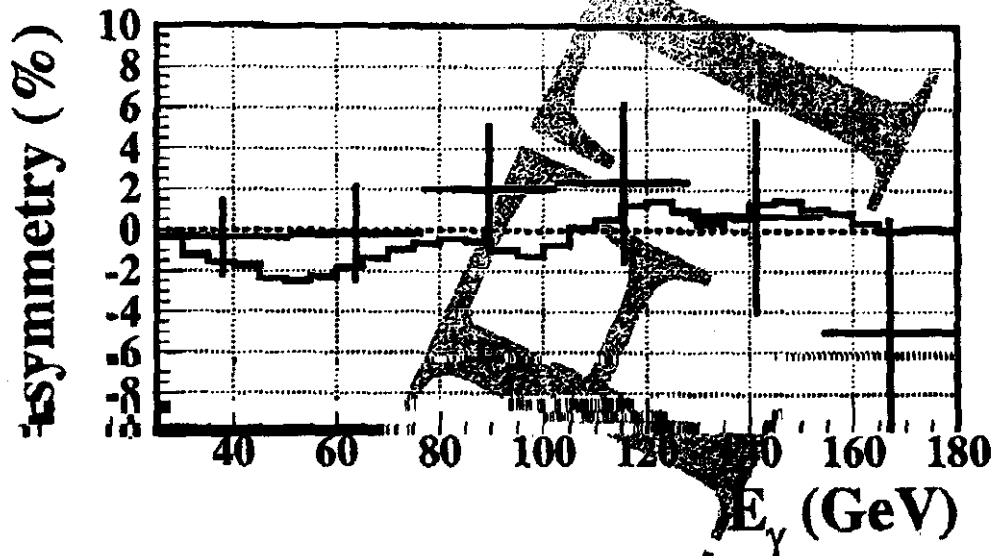


FIG. 8: Asymmetry of the  $e^+e^-$  pair production in the aligned diamond crystal as a function of the photon energy  $E_\gamma$  which is measured to determine the  $P_1$  component of the photon polarization in the SOS-aligned Si crystal by 178 GeV electrons. The black crosses are the measurements and the red histogram represent the MC prediction.

transverse potential in the electron channels in between crystallographic planes. (3) Coherent bremsstrahlung (CB) induced by the longitudinal variation of the potential due to the periodic structure of the atomic strings in the crystal that are crossed by the electron. The recent calculations have taken these processes into account.

Since the electron experiences both the transverse potential (channelling radiation) and the longitudinal potential (CB) the spectrum of the emitted radiation should show frequency components characteristic to both phenomena along with possible mixed frequencies. The low energy part of the radiation spectrum is identified in the MC simulations to the channelling radiation with negligible linear polarization and the high energy peak corresponds to the coherent bremsstrahlung (CB) with negligible linear polarization.

#### Acknowledgments

We dedicate this work to the memory of Friedel Sellschop. We express our gratitude to CNRS, Grenoble for the crystal alignment and Messers DeBeers Corporation for providing the high quality synthetic diamonds. We are grateful for the help and support of N. Doble, K. Elsener and H. Wahl. It is a pleasure to thank the technical staff of the participat-